

**Search Notes**

Application/Control No.

10/511,791

Examiner

John E. Chapman

Applicant(s)/Patent under  
Reexamination

AKIYAMA ET AL.

Art Unit

2856

**SEARCHED**

Class	Subclass	Date	Examiner
73	598 600 620 644	9/24/2007	JC
209	590	9/24/2007	JC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR